

Notice of References Cited	Application/Control No. 10/620,376	Applicant(s)/Patent Under Reexamination HAYASHI ET AL.	
	Examiner Dah-Wei D. Yuan	Art Unit 1745	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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